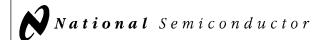
±25 mV

 $\pm\,5V$ 



# DS1652/DS3650/DS3652 **Quad Differential Line Receivers**

#### **General Description**

The DS3650 and DS1652/DS3652 are TTL compatible quad high speed circuits intended primarily for line receiver applications. Switching speeds have been enhanced over conventional line receivers by the use of Schottky technology, and TRI-STATE® strobing is incorporated offering a high impedance output state for bussed organizations.

The DS3650 has active pull-up outputs and offers a TRI-STATE strobe, while the DS1652/DS3652 offers open collector outputs providing implied "AND" operation.

The DS1652/DS3652 can be used for address decoding as illustrated below. All outputs of the DS1652/DS3652 are tied together through a common resistor to 5V. In this con-

figuration, the DS1652/DS3652 provides the "AND" function. All addresses have to be true before the output will go high. This scheme eliminates the need for an "AND" gate and enhances speed throughput for address decoding.

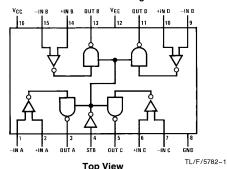
#### **Features**

- High speed
- TTL compatible
- Input sensitivity
- TRI-STATE outputs for high speed busses
- Standard supply voltages

■ Pin and function compatible with MC3450 and MC3452

#### **Connection Diagram**

#### **Dual-In-Line Package**



Order Number DS3650M, DS3652M or DS3650N See NS Package Number M16A or N16A For Complete Military 883 Specifications, see RETS Data Sheet.

Order Number DS1652J See NS Package Number J16A

#### **Truth Table**

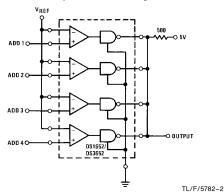
		Output			
Input	Strobe	DS3650	DS1652/ DS3652		
$V_D \ge 25 \text{ mV}$	L	Н	Open		
	Н	Open	Open		
$-25 \text{ mV} \le V_{\text{ID}} \le 25 \text{ mV}$	L	Х	Х		
	Н	Open	Open		
$V_{ID} \leq -25 \text{ mV}$	L	L	L		
	н	Open	Open		

 $\mathsf{L} = \mathsf{Low}\;\mathsf{Logic}\;\mathsf{State}\quad\mathsf{Open} = \mathsf{TRI}\text{-}\mathsf{STATE}$ 

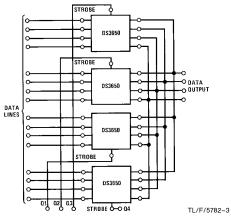
H = High Logic State X = Indeterminate State TRI-STATE® is a registered trademark of National Semiconductor Corporation.

## **Typical Applications**

#### Implied "AND" Gating



#### Wired "OR" Data Selecting Using TRI-STATE Logic



### Absolute Maximum Ratings (Note 1)

If Military/Aerospace specified devices are required, please contact the National Semiconductor Sales Office/Distributors for availability and specifications.

Power Supply Voltages

rower supply voltages	
$V_{CC}$	+7.0 V <sub>DC</sub>
$V_{EE}$	$-7.0 V_{DC}$
Differential-Mode Input Signal Voltage	
Range, V <sub>IDR</sub>	$\pm6.0~V_{DC}$
Common-Mode Input Voltage Range, VIC	$\pm 5.0  V_{DC}$
Strobe Input Voltage, VI(S)	5.5 V <sub>DC</sub>
Storage Temperature Range	$-65^{\circ}\text{C}$ to $+150^{\circ}\text{C}$
Lead Temperature (Soldering, 4 seconds	s) 260°C
Maximum Power Dissipation* at 25°C	
Cavity Package	1509 mW
Molded DIP Package	1476 mW
SO Package	1051 mW
*Derate cavity package 10.1 mW/°C above 25°C;	derate molded DIP pack-
age 11.8 mW/°C above 25°C; derate SO package 8	3.41 mW/°C above 25°C.

Operating Conditions								
	Min	Max	Units					
Supply Voltage, V <sub>CC</sub>								
DS1652	4.5	5.5	$V_{DC}$					
DS3650, DS3652	4.75	5.25	$V_{DC}$					
Supply Voltage, V <sub>EE</sub>								
DS1652	-4.5	-5.5	$V_{DC}$					
DS3650, DS3652	-4.75	-5.25	$V_{DC}$					
Operating Temperature, T <sub>A</sub>								
DS1652	-55	+125	°C					
DS3650, DS3652	0	+70	°C					
Output Load Current, IOL		16	mA					
Differential-Mode Input								
Voltage Range, V <sub>IDR</sub>	-5.0	+5.0	$V_{DC}$					
Common-Mode Input								
Voltage Range, V <sub>ICR</sub>	-3.0	+3.0	$V_{DC}$					
Input Voltage Range								
Input to GND, VIR	-5.0	+3.0	$V_{DC}$					

### **Electrical Characteristics**

(V\_{CC} = 5.0 V\_{DC}, V\_{EE} = -5.0 V\_{DC}, Min  $\leq$   $T_{A} \leq$  Max, unless otherwise noted) (Notes 2 and 3)

Symbol	Parameter	Cond	Conditions			Max	Units
V <sub>IS</sub>	Input Sensitivity, (Note 5) (Common-Mode Voltage Range = $-3V \le V_{\text{IN}} \le 3V$ )	$\begin{aligned} & \text{Min} \leq \text{V}_{CC} \leq \text{Max} \\ & \text{Min} \geq \text{V}_{EE} \geq \text{Max} \end{aligned}$				±25.0	mV
I <sub>IH(I)</sub>	High Level Input Current to Receiver Input	(Figure 5)				75	μΑ
I <sub>IL(I)</sub>	Low Level Input Current to Receiver Input	(Figure 6)				-10	μΑ
I <sub>IH(S)</sub>	High Level Input Current to Strobe Input	(Figure 3)	V <sub>IH(S)</sub> = 2.4V, DS1652			100	μΑ
			V <sub>IH(S)</sub> = 2.4V, DS3650, DS3652			40	μΑ
			$V_{IH(S)} = V_{CC}$			1	mA
I <sub>IL(S)</sub>	Low Level Input Current to Strobe Input		$V_{IH(S)} = 0.4V$			-1.6	mA
V <sub>OH</sub>	High Level Output Voltage	(Figure 1)	DS3650	2.4			V
I <sub>CEX</sub>	High Level Output Leakage Current	(Figure 1)	DS1652, DS3652			250	μΑ
V <sub>OL</sub>	Low Level Output Voltage	(Figure 1)	DS3650, DS3652			0.45	v
			DS1652			0.50	, v
los	Short-Circuit Output Current (Note 4)	(Figure 4)	DS3650	-18		-70	mA
loff	Output Disable Leakage Current	(Figure 7)	DS3650			40	μΑ

#### **Electrical Characteristics**

(V<sub>CC</sub> = 5.0 V<sub>DC</sub>, V<sub>EE</sub> = -5.0 V<sub>DC</sub>, Min  $\leq$  T<sub>A</sub>  $\leq$  Max, unless otherwise noted) (Notes 2 and 3) (Continued)

Symbol	Parameter	Conditions		Min	Тур	Max	Units
Іссн	High Logic Level Supply Current from V <sub>CC</sub>	(Figure 2)			45	60	mA
IEEH	High Logic Level Supply Current from V <sub>EE</sub>	(Figure 2)			-17	-30	mA

Note 1: "Absolute Maximum Ratings" are those values beyond which the safety of the device cannot be guaranteed. Except for "Operating Temperature Range" they are not meant to imply that the devices should be operated at these limits. The table of "Electrical Characteristics" provides conditions for actual device operation.

Note 2: Unless otherwise specified, min/max limits apply across the 0°C to +70°C range for the DS3650, DS3652 and the -55°C to +125°C range for the DS1652. All typical values are for T<sub>A</sub> = 25°C, V<sub>CC</sub> = 5V and V<sub>EE</sub> = -5V.

Note 3: All currents into device pins shown as positive, out of device pins as negative, all voltages referenced to ground unless otherwise noted. All values shown as max or min on absolute value basis.

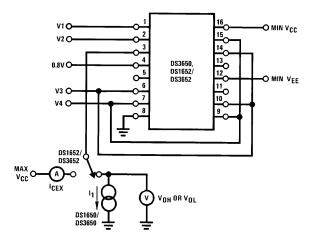
Note 4: Only one output at a time should be shorted.

Note 5: A parameter which is of primary concern when designing with line receivers is, what is the minimum differential input voltage required as the receiver input terminals to guarantee a given output logic state. This parameter is commonly referred to as threshold voltage. It is well known that design considerations of threshold voltage are plagued by input offset currents, bias currents, network source resistances, and voltage gain. As a design convenience, the DS1652 and the DS3650, DS3652 are specified to a parameter called input sensitivity (V<sub>IS</sub>). This parameter takes into consideration input offset currents and bias currents and guarantees a minimum input differential voltage to cause a given output logic state with respect to a maximum source impedance of 2000 at each input.

### **Switching Characteristics** ( $V_{CC} = 5 V_{DC}$ , $V_{EE} = -5 V_{DC}$ , $T_A = 25 ^{\circ}C$ unless otherwise noted)

Symbol	Parameter	Co	Conditions		Тур	Max	Units
t <sub>PHL(D)</sub>	High-to-Low Logic Level Propagation		DS3650		21	25	ns
	Delay Time (Differential Inputs)	(Figure 8)	DS1652/DS3652		20	25	ns
t <sub>PLH(D)</sub>	Low-to-High Logic Level Propagation	(riguro o)	DS3650		20	25	ns
	Delay Time (Differential Inputs)		DS1652/DS3652		22	25	ns
t <sub>POH(S)</sub>	TRI-STATE to High Logic Level Propagation Delay Time (Strobe)		DS3650		16	21	ns
t <sub>PHO(S)</sub>	High Logic Level to TRI-STATE Propagation Delay Time (Strobe)	(Figure 9)	DS3650		7	18	ns
t <sub>POL(S)</sub>	TRI-STATE to Low Logic Level Propagation Delay Time (Strobe)	(Figure 9)	DS3650		19	27	ns
t <sub>PLO(S)</sub>	Low Logic Level to TRI-STATE Propagation Delay Time (Strobe)		DS3650		14	29	ns
t <sub>PHL(S)</sub>	High-to-Low Logic Level Propagation Delay Time (Strobe)	(Figure 10)	DS1652/DS3652		16	25	ns
t <sub>PLH(S)</sub>	Low-to-High Logic Level Propagation Delay Time (Strobe)	( iguic 10)	DS1652/DS3652		13	25	ns

### **Electrical Characteristic Test Circuits**



TL/F/5782-4

	V	1	V	2	,	/3	V4			
	DS3650	DS1652/ DS3652	DS3650	DS1652/ DS3652	DS3650	DS1652/ DS3652	DS3650	DS1652/ DS3652	l <sub>1</sub>	
V <sub>OH</sub>	+2.975V -3.0V		+3.0V -2.975V		+3.0V GND		GND -3.0V		−0.4 mA −0.4 mA	
I <sub>CEX</sub>		+2.975V -3.0V		+3.0V -2.975V		+3.0V GND		GND -3.0V		
V <sub>OL</sub>	+3.0V -2.975V	+3.0V -2.975V	+2.975V -3.0V	+2.975V -3.0V	GND -3.0V	GND -3.0V	+3.0V GND	+3.0V GND	+ 16 mA + 16 mA	
Channe	Channel A shown under test. Other channels are tested similarly.  FIGURE 1. I <sub>CEX</sub> , V <sub>OH</sub> and V <sub>OL</sub>									

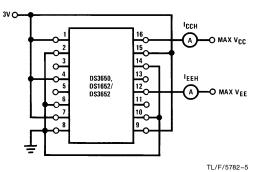


FIGURE 2.  $I_{\mbox{\footnotesize CCH}}$  and  $I_{\mbox{\footnotesize EEH}}$ 

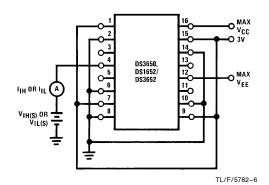
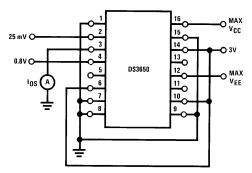


FIGURE 3.  $I_{\mbox{\scriptsize IH(S)}}$  and  $I_{\mbox{\scriptsize IL(S)}}$ 

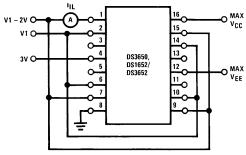
### **Electrical Characteristic Test Circuits (Continued)**



TL/F/5782-7

**Note:** Channel A shown under test, other channels are tested similiarly. Only one output shorted at a time.

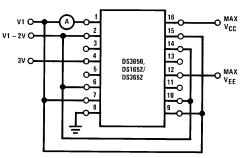
FIGURE 4. I<sub>OS</sub>



TL/F/5782-9

Note: Channel A(-) shown under test, other channels are tested similarly. Devices are tested with V1 from 3V to  $-3\mathrm{V}.$ 

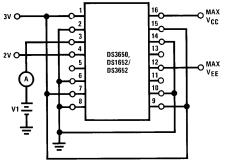
FIGURE 6. I<sub>IL</sub>



TL/F/5782-8

Note: Channel A(-) shown under test, other channels are tested similarly. Devices are tested with V1 from 3V to -3V.

FIGURE 5. I<sub>IH</sub>

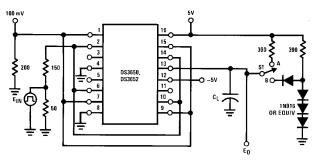


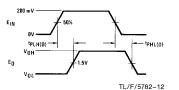
TL/F/5782-10

Note: Output of Channel A shown under test, other outputs are tested similarly for V1  $\,=\,$  0.4V and 2.4V.

FIGURE 7. I<sub>OFF</sub>

## **AC Test Circuits and Switching Time Waveforms**





Note: E<sub>IN</sub> waveform characteristics: : EIN waveform characteristics:  $t_{LH}$  and  $t_{THL} \le 10$  ns measured 10% to 90% PRR = 1 MHz Duty Cycle = 50%

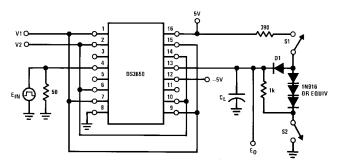
TL/F/5782-11

Note: Output of Channel B shown under test, other channels are tested similarly.

S1 at "A" for DS1652/DS3652 S1 at "B" for DS1650/DS3650  $C_L=15\ pF$  total for DS1652/DS3652

 $C_L = 50 \text{ pF total for DS1650/DS3650}$ 

FIGURE 8. Receiver Propagation Dealy t<sub>PLH(D)</sub> and t<sub>PHL(D)</sub>



TL/F/5782-13

Note: Output of Channel B shown under test, other channels are tested similiarly.

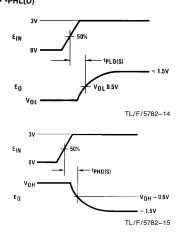
	V1	V2	S1	S2	CL
t <sub>PLO(S)</sub>	100 mV	GND	Closed	Closed	15 pF
t <sub>POL(S)</sub>	100 mV	GND	Closed	Open	50 pF
t <sub>PHO(S)</sub>	GND	100 mV	Closed	Closed	15 pF
t <sub>POH(S)</sub>	GND	100 mV	Open	Closed	50 pF

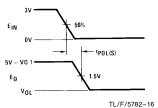
 $\mathbf{C}_{\mathsf{L}}$  includes jig and probe capacitance.

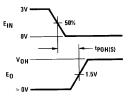
 $E_{IN}$  waveform characteristics:  $t_{TLH}$  and  $t_{THL} \leq$  10 ns measured 10% to 90%

PRR = 1 MHz

Duty Cycle = 50%



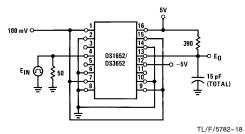


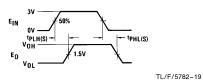


TL/F/5782-17

FIGURE 9. Strobe Propagation Delay  $t_{PLO(S)}, t_{POL(S)}, t_{PHO(S)}$  and  $t_{POH(S)}$ 

# AC Test Circuits and Switching Time Waveforms (Continued)



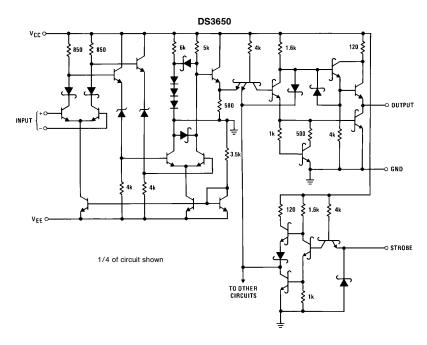


Note:  $E_{IN}$  waveform characteristics:  $t_{TLH}$  and  $t_{THL} \le 10$  ns measured 10% and 90% PRR = 1 MHz Duty Cycle = 500 ns

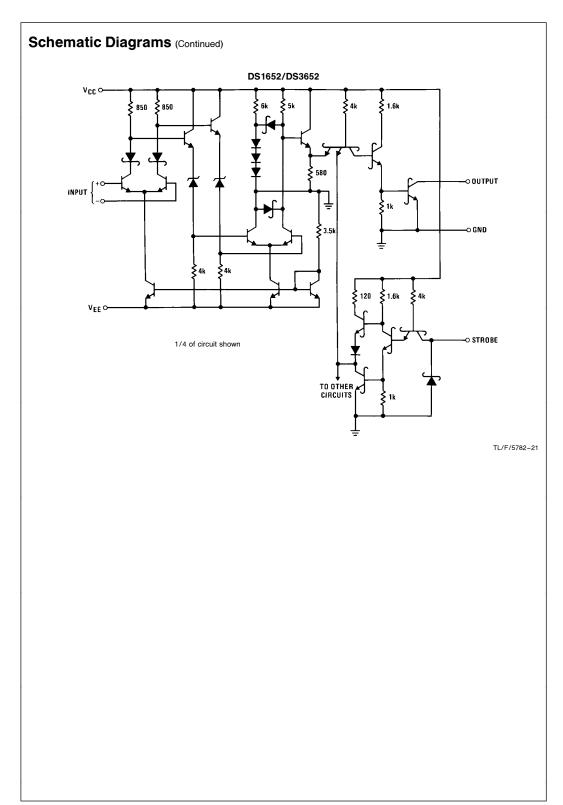
**Note:** Output of Channel B shown under test, other channels are tested similarly.

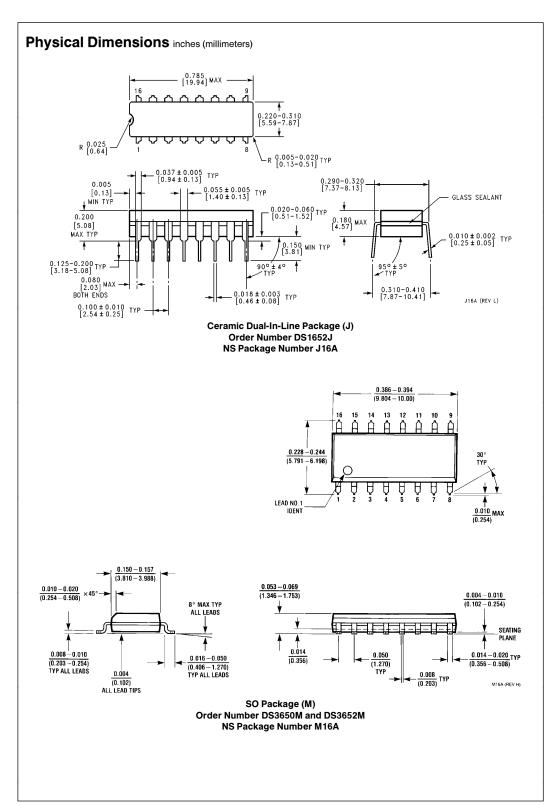
FIGURE 10. Strobe Propagation Delay  $t_{\mbox{\scriptsize PLH}(\mbox{\scriptsize S})}$  and  $t_{\mbox{\scriptsize PHL}(\mbox{\scriptsize S})}$ 

# **Schematic Diagrams**

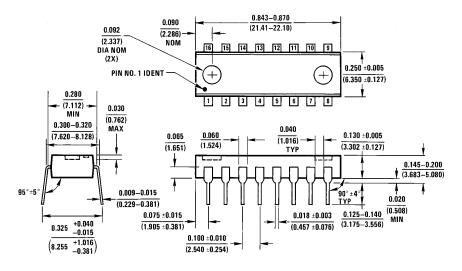


TL/F/5782-20





### Physical Dimensions inches (millimeters) (Continued)



Molded Dual-In-Line Package (N) Order Number DS3650N NS Package Number N16A

#### LIFE SUPPORT POLICY

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- 2. A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

N16A (REV E)



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